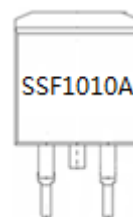
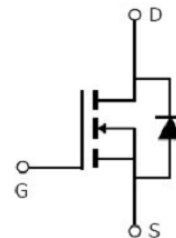


Main Product Characteristics:

V_{DSS}	100V
$R_{DS(on)}$	9.5mohm(typ.)
I_D	100A


D2PAK

**Marking and pin
Assignment**

Schematic diagram
Features and Benefits:

- Advanced trench MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 175°C operating temperature


Description:

It utilizes the latest trench processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications

Absolute max Rating:

Symbol	Parameter	Max.	Units
$I_D @ TC = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ ①	100	A
$I_D @ TC = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ ①	70	
I_{DM}	Pulsed Drain Current②	400	
$P_D @ TC = 25^\circ C$	Power Dissipation③	205	W
	Linear Derating Factor	1.3	W/°C
V_{DS}	Drain-Source Voltage	100	V
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}	Single Pulse Avalanche Energy @ $L=1.28mH$	576	mJ
I_{AS}	Avalanche Current @ $L=1.28mH$	30	A
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to + 175	°C

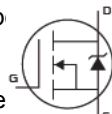
Thermal Resistance

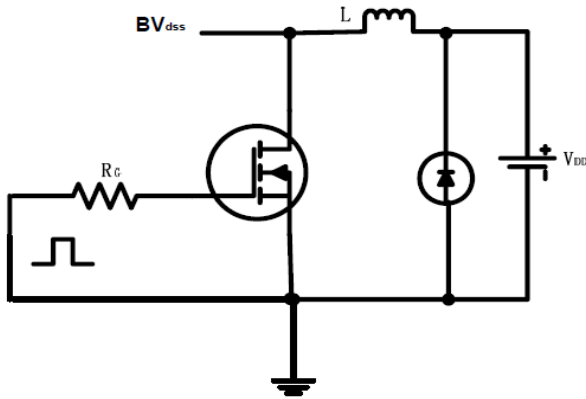
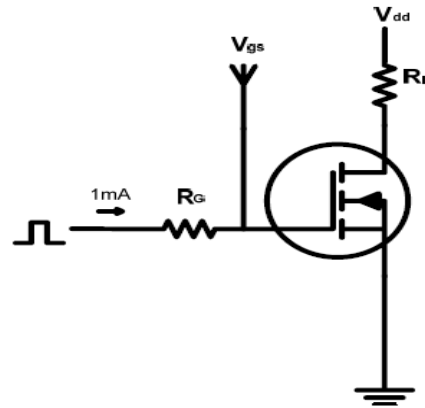
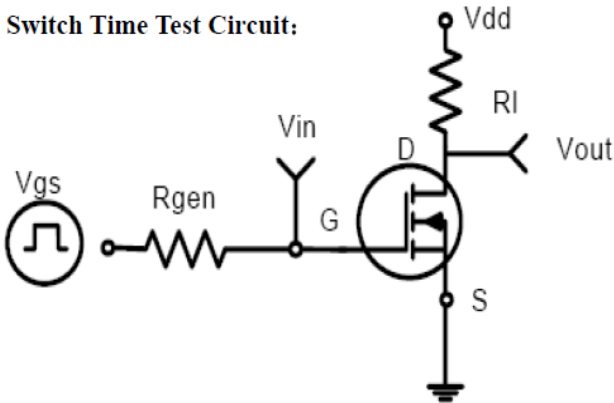
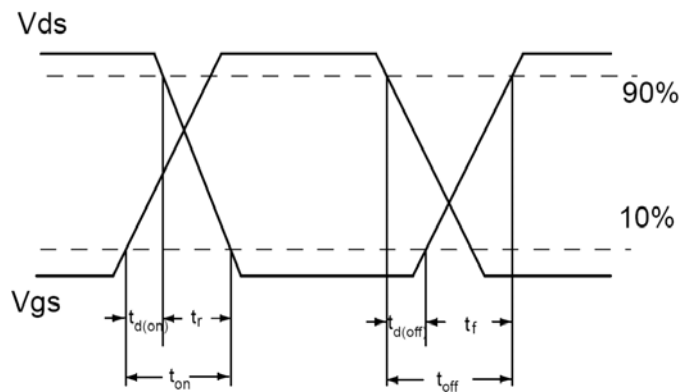
Symbol	Characterizes	Typ.	Max.	Units
R _{θJC}	Junction-to-case ^③	—	0.73	°C /W
R _{θJA}	Junction-to-ambient (t ≤ 10s) ^④	—	62	°C /W
	Junction-to-Ambient (PCB mounted, steady-state) ^④	—	40	°C /W

Electrical Characterizes @T_A=25°C unless otherwise specified

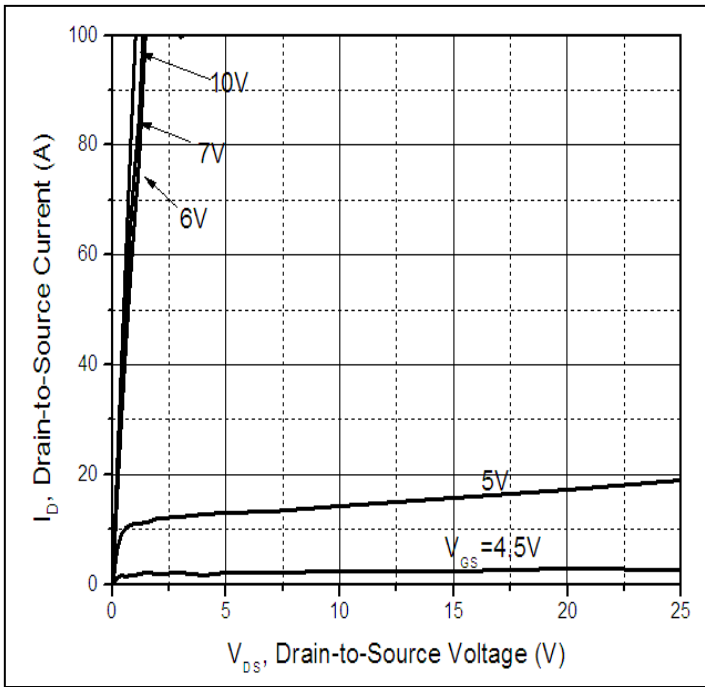
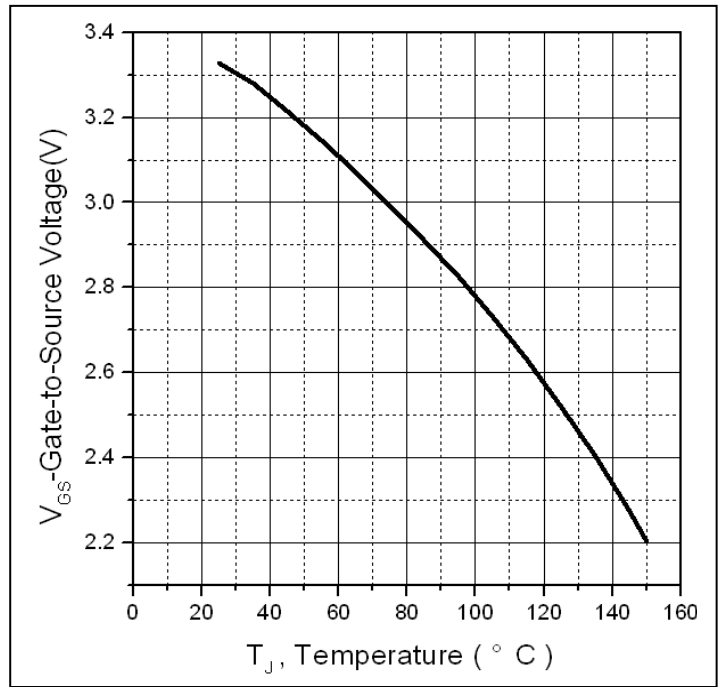
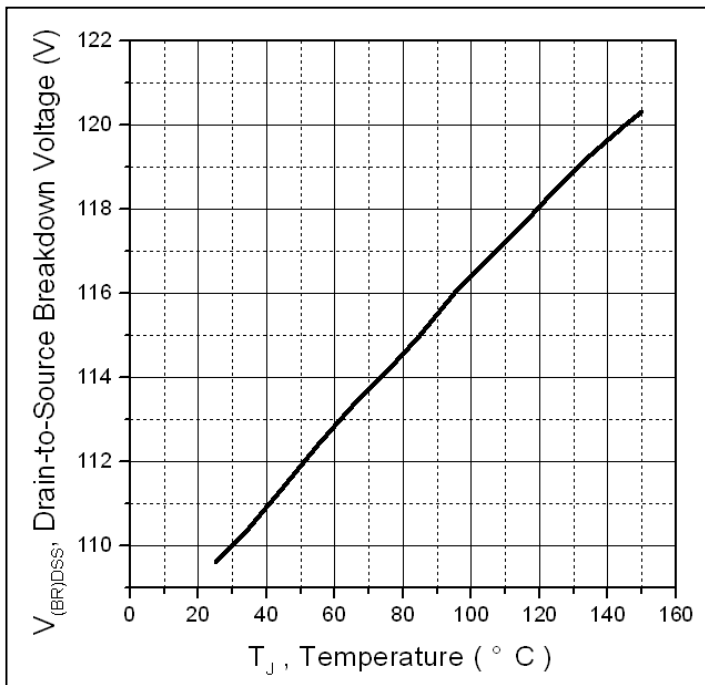
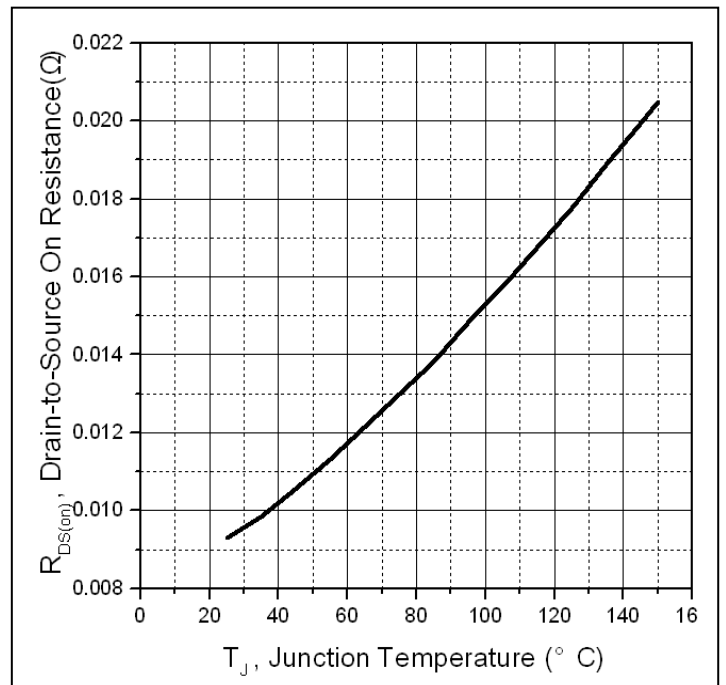
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	100	—	—	V	V _{GS} = 0V, I _D = 250μA
R _{DS(on)}	Static Drain-to-Source on-resistance	—	9.5	10	mΩ	V _{GS} =10V, I _D = 30A T _J = 125°C
		—	17.8	—		
V _{GS(th)}	Gate threshold voltage	2	—	4	V	V _{DS} = V _{GS} , I _D = 250μA T _J = 125°C
		—	2.52	—		
I _{DSS}	Drain-to-Source leakage current	—	—	1	μA	V _{DS} = 100V, V _{GS} = 0V T _J = 125°C
		—	—	50		
I _{GSS}	Gate-to-Source forward leakage	—	—	100	nA	V _{GS} = 20V
		-100	—	—		V _{GS} = -20V
Q _g	Total gate charge	—	120	—	nC	I _D = 30A, V _{DS} =30V, V _{GS} = 10V
Q _{gs}	Gate-to-Source charge	—	24	—		
Q _{gd}	Gate-to-Drain("Miller") charge	—	45	—		
t _{d(on)}	Turn-on delay time	—	39	—	ns	V _{GS} =10V, V _{DS} =30V, R _L =15Ω, R _{GEN} =2.5Ω I _D =2A
t _r	Rise time	—	67	—		
t _{d(off)}	Turn-Off delay time	—	221	—		
t _f	Fall time	—	79	—		
C _{iss}	Input capacitance	—	5688	—	pF	V _{GS} = 0V V _{DS} = 25V f = 1MHz
C _{oss}	Output capacitance	—	312	—		
C _{rss}	Reverse transfer capacitance	—	287	—		

Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)	—	—	100	A	MOSFET symb showing the integral reverse p-n junction diode. 
I _{SM}	Pulsed Source Current (Body Diode)	—	—	400	A	
V _{SD}	Diode Forward Voltage	—	0.85	1.3	V	I _S =60A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	—	51	—	ns	T _J = 25°C, I _F = 75A, di/dt =
Q _{rr}	Reverse Recovery Charge	—	135	—	nC	100A/μs

Test circuits and Waveforms
EAS test circuits:

Gate charge test circuit:

Switch Time Test Circuit:

Switch Waveforms:

Notes:

- ① The maximum current rating is limited by bond-wires.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of $R_{\theta JA}$ is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$
- ⑤ These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)} = 175^\circ\text{C}$.
- ⑥ The maximum current rating is limited by bond-wires.

Typical electrical and thermal characteristics

Figure 1: Typical Output Characteristics

Figure 2. Gate to source cut-off voltage

Figure 3. Drain-to-Source Breakdown Voltage vs. Temperature

Figure 4: Normalized On-Resistance Vs. Case Temperature

Typical electrical and thermal characteristics

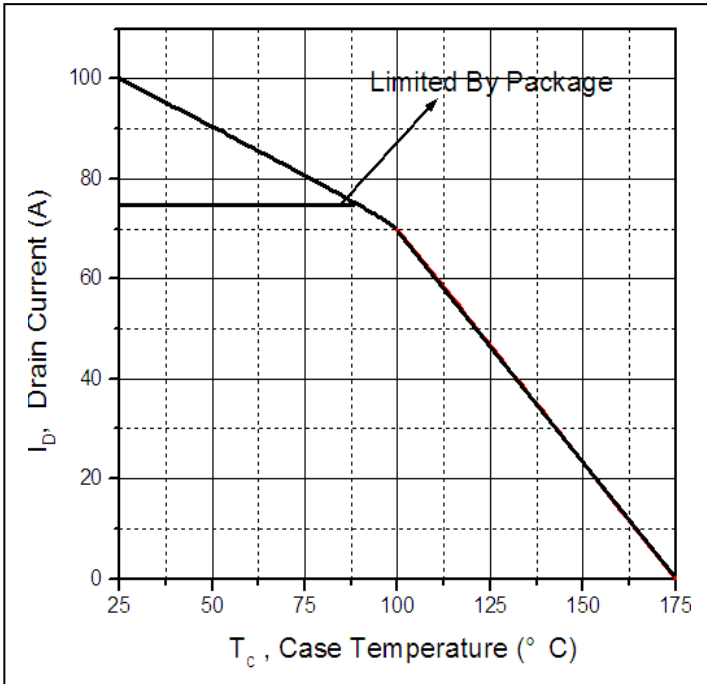


Figure 5. Maximum Drain Current Vs. Case Temperature

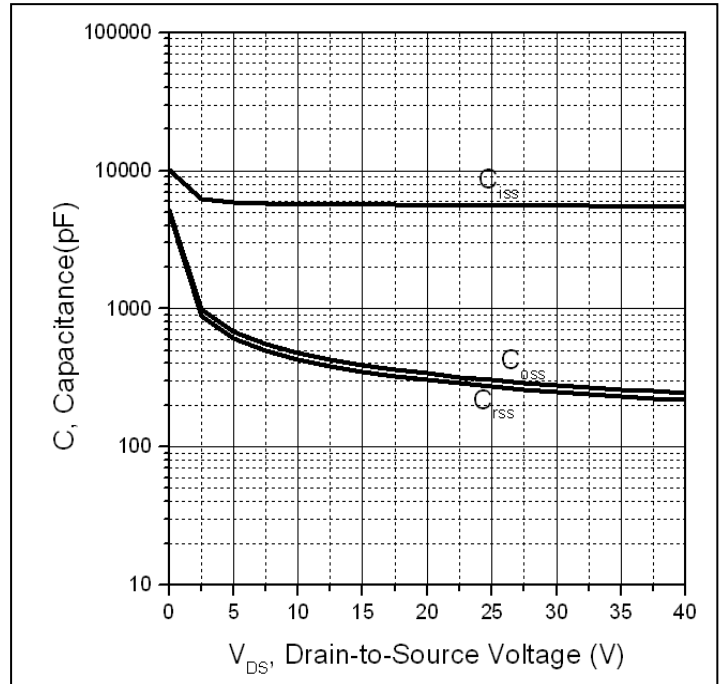


Figure 6. Typical Capacitance Vs. Drain-to-Source Voltage

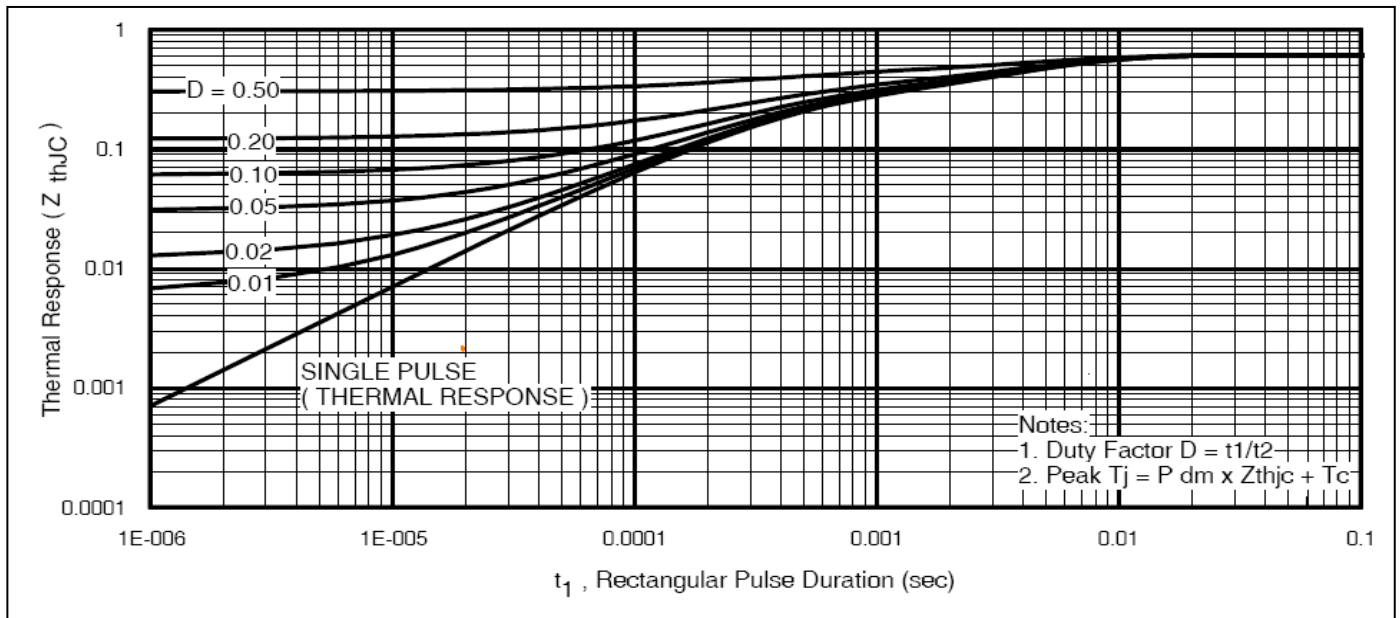
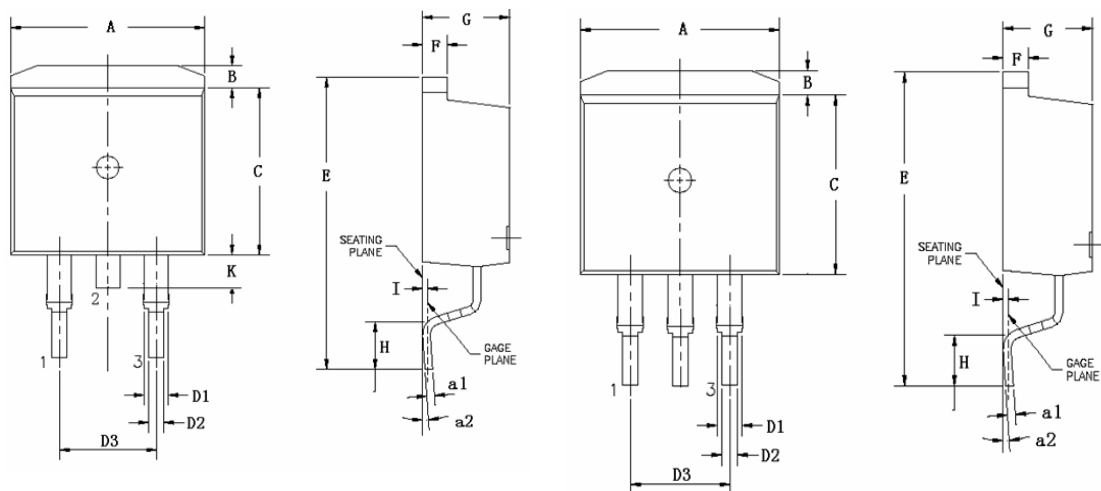


Figure 7. Maximum Effective Transient Thermal Impedance, Junction-to-Case

Mechanical Data:
D2PAK PACKAGE OUTLINE DIMENSION


Symbol	Dimension In Millimeters		Dimension In Inches	
	Min	Max	Min	Max
A	9.660	10.280	0.380	0.405
B	1.020	1.320	0.040	0.052
C	8.590	9.400	0.338	0.370
D1	1.140	1.400	0.045	0.055
D2	0.700	0.950	0.028	0.037
D3	5.080 (TYP)		0.200 (TYP)	
E	15.090	15.390	0.594	0.606
F	1.150	1.400	0.045	0.055
G	4.300	4.700	0.169	0.185
H	2.290	2.790	0.090	0.110
I	0.250 (TYP)		0.010 (TYP)	
K	1.300	1.600	0.051	0.063
a1	0.450	0.650	0.018	0.026
a2	0°	8°	1°	8°

Ordering and Marking Information
Device Marking: SSF1010A

Package (Available)
D2PAK(TO263)
Operating Temperature Range
C : -55 to 175 °C

Devices per Unit

Package Type	Units/Tube	Tubes/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
D2PAK	50	20	1000	6	6000

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High Temperature Reverse Bias(HTRB)	$T_j=125^{\circ}\text{C}$ to 175°C @ 80% of Max $V_{DSS}/V_{CES}/V_R$	168 hours 500 hours 1000 hours	3 lots x 77 devices
High Temperature Gate Bias(HTGB)	$T_j=150^{\circ}\text{C}$ or 175°C @ 100% of Max V_{GSS}	168 hours 500 hours 1000 hours	3 lots x 77 devices

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